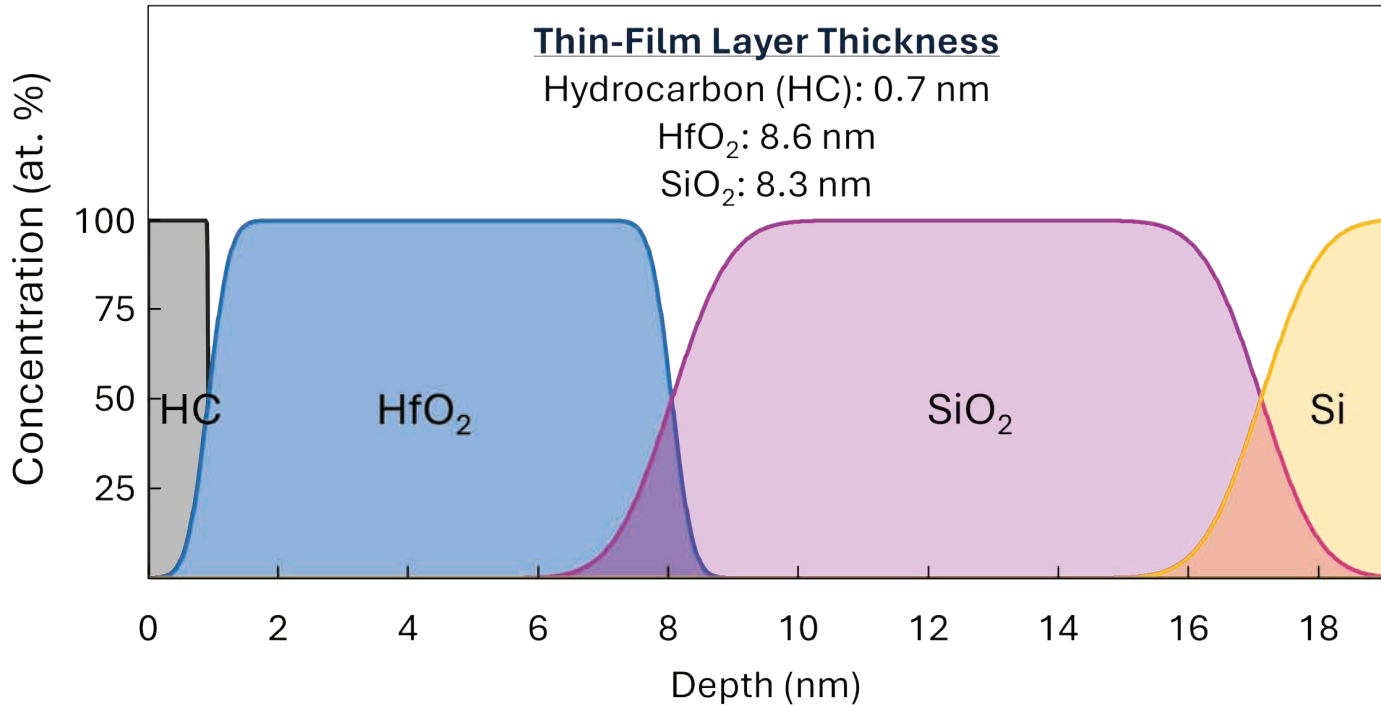




# StrataPHI 3.0

## Next Generation Thin Film Intelligence



### Non-Destructive Ultra-Thin Film Software for R&D and Quality Control

- Multi-layer thin films from monolayer to 30 nm in thickness from XPS/HAXPES
- No additional instrument hardware or reference samples required
- **NEW!** Updated user interface featuring colorized depth profiles
- **NEW!** RSF Optimization mode: materials properties editor for accurate modeling of engineered materials

### Rapid and Precise Film Thickness Analysis

- **NEW!** Integrated Analyzer Acceptance Angle mode: full angular range of electrons from sample for precise film thickness
- Automated, real-time batch processing for metrology
- *StrataPHI* Process Record (SPR) files save optimized model for future analysis
- Export to Microsoft Excel™, PowerPoint™, and text files

### Fractional Coverage of Ultra-Thin Layers

- Simultaneous fractional coverage and thickness of monolayer on substrate
- Consistent with optical microscopy and low energy ion scattering (LEIS)